

Supplementary Materials: Effect of SnO₂ Colloidal Dispersion Solution Concentration on the Quality of Perovskite Layer of Solar Cells

Keke Song, Xiaoping Zou *, Huiyin Zhang *, Chunqian Zhang, Jin Cheng, Baoyu Liu, Yujun Yao, Xiaolan Wang, Xiaotong Li, Yifei Wang and Baokai Ren

Beijing Advanced Innovation Center for Materials Genome Engineering, Research Center for Sensor Technology, Beijing Key Laboratory for Sensor, MOE Key Laboratory for Modern Measurement and Control Technology, School of Instrument Science and Opto Electronics Engineering, Beijing Information Science and Technology University, Beijing 100101, China; songmengke163@163.com (K.S.); chunqiancool@163.com (C.Z.); chengjin@bistu.edu.cn (J.C.); liubaoyu0214@163.com (B.L.); yyj10zy@gmail.com (Y.Y.); wangxl1105@163.com (X.W.); xiaotong252240@163.com; yifei wang2020@126.com (Y.W.); renbk2021@163.com (B.R.)

* Correspondence: xpzou2020@bistu.edu.cn; zhy@bistu.edu.cn; Tel.: +86-1364-105-6404(X.Z.)
+86-1860-084-3626(H.Z.)

Table S1. Hall effect measurements of SnO₂ film.

SnO ₂ Colloidal Dispersion Solution Concentration	Conductivity (μS/cm)	Mobility (cm ² ·V ⁻¹ ·S ⁻¹)	Carrier concentration (cm ⁻³)
10 wt. %	7.5×10^{-2}	51.6	9.0×10^{12}
6.67 wt. %	3.0×10^{-2}	42.6	4.5×10^{12}
5 wt. %	2.3×10^{-2}	35.5	4.0×10^{12}

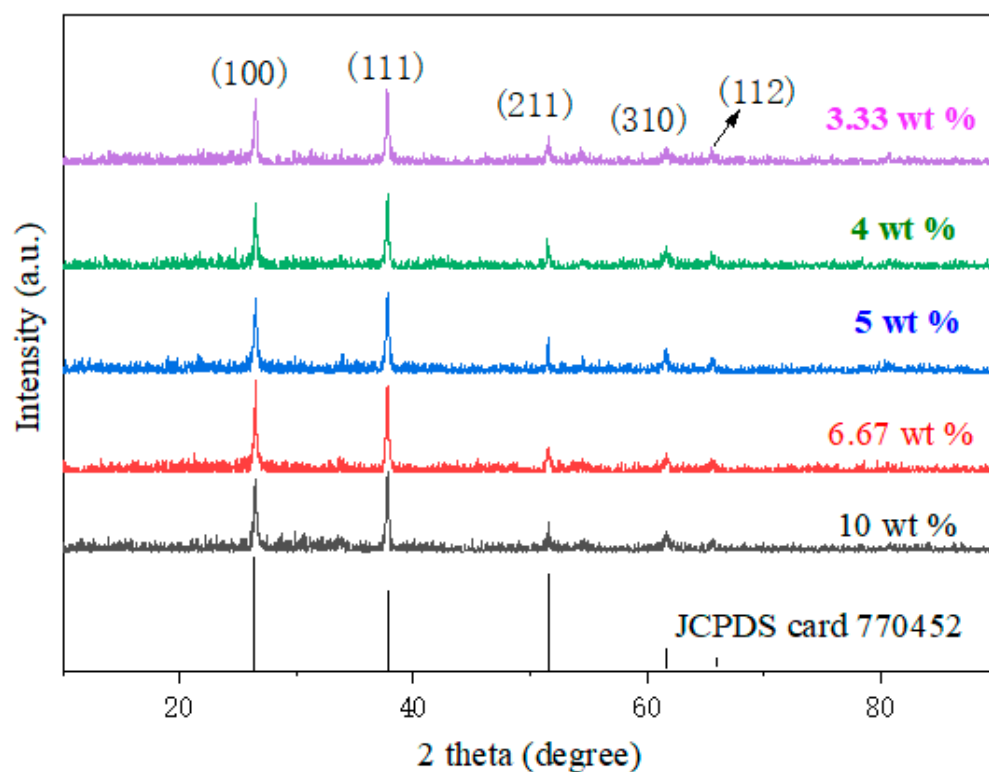


Figure S1. The XRD patterns of the original layers of SnO₂ with different concentrations of SnO₂ colloidal dispersion solution.

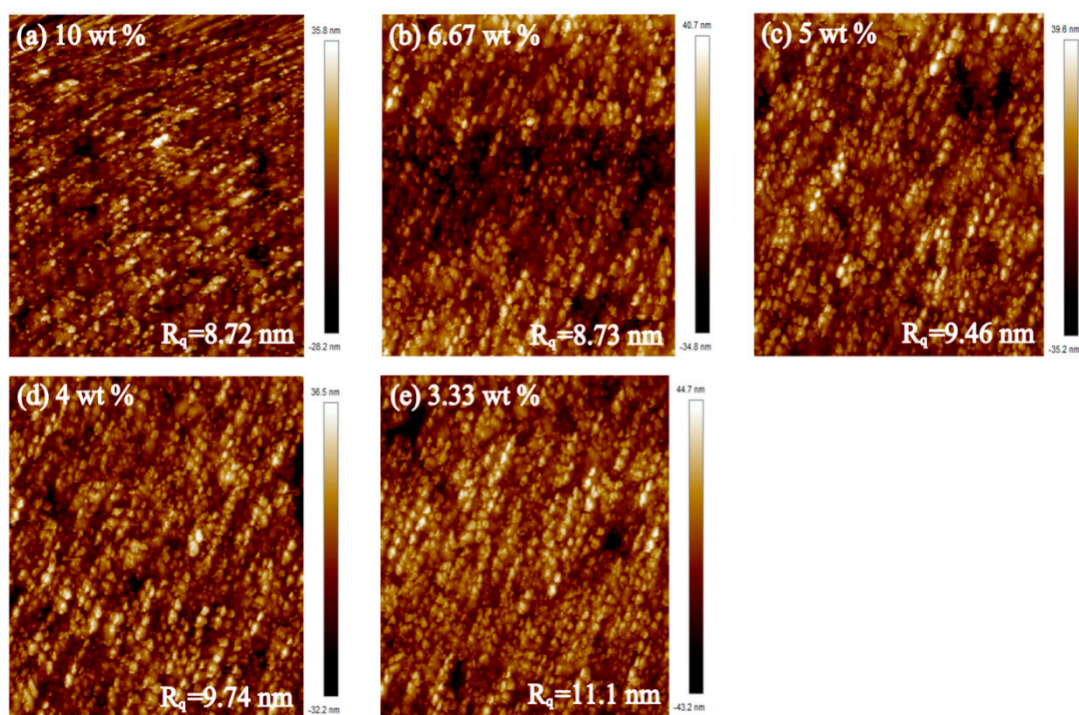


Figure S2. Atomic Force Microscope (AFM) of different concentrations of SnO₂ colloidal dispersion solution. SnO₂ colloid solutions of different concentrations: (a) 10 wt.%, (b) 6.67 wt.%, (c) 5 wt.%, (d) 4 wt.%, and (e) 3.33 wt.%. The roughness of the films is recorded on the right side of the images.